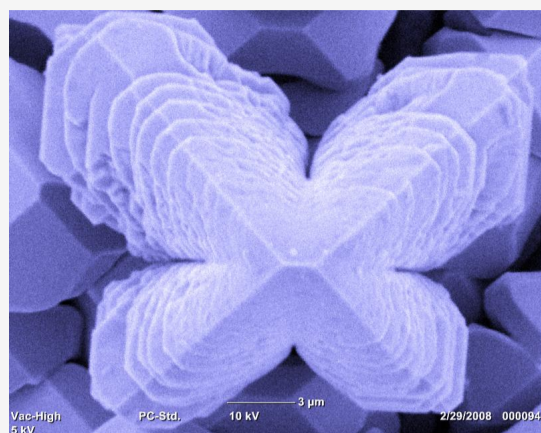


Extreme Image



Icy blue false color image of a dendrite taken on the JEOL NeoScope benchtop SEM. For more examples of this versatile little SEM, visit our [gallery of images](#).

See Us at These Upcoming Meetings & Tradeshows in 2010!

SPIE Advanced Lithography

21 - 25 February 2010
San Jose Convention Center
San Jose, California

American Academy of Forensic Sciences

22 - 27 February 2010
Washington State Convention & Trade Center
Seattle, Washington

Pittcon

1 - 4 March 2010
Orange County Convention Center
Orlando, Florida

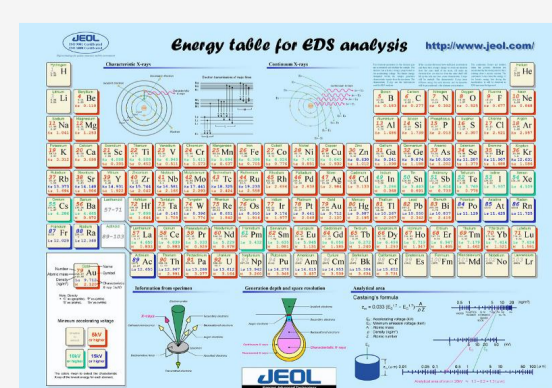
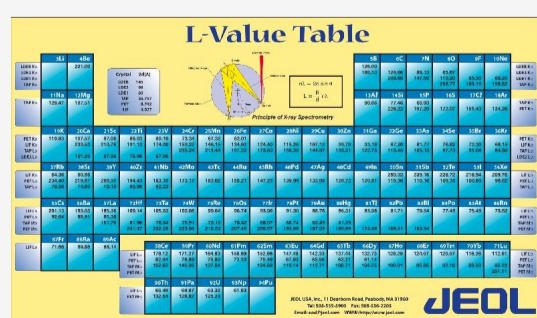
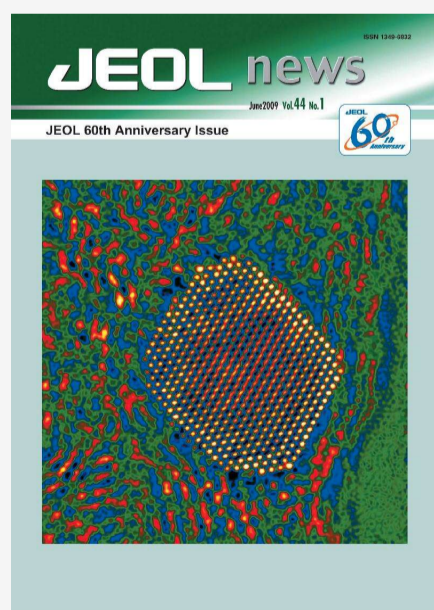
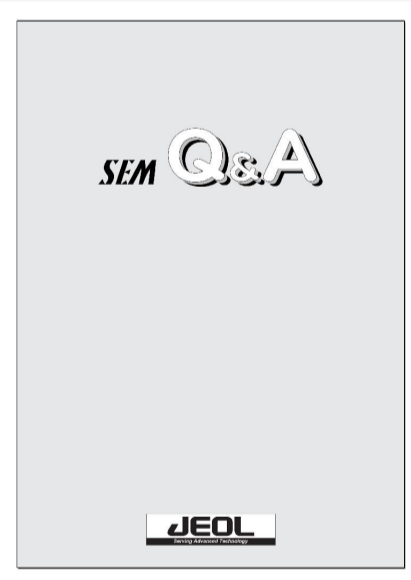
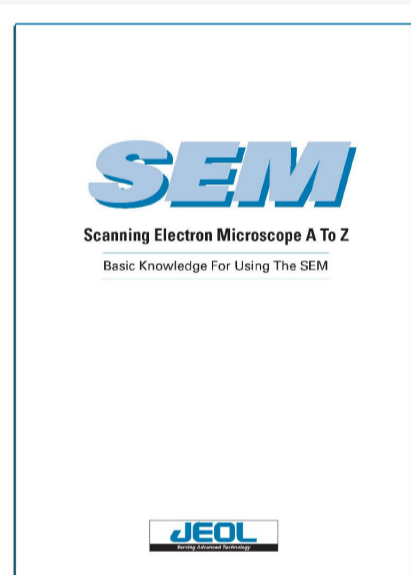
More events for 2010 coming soon.

JEOL Microscopy in the News

[U. of C. Treasure Really Just a Fake](#)

[Making SEMs More Micro](#)

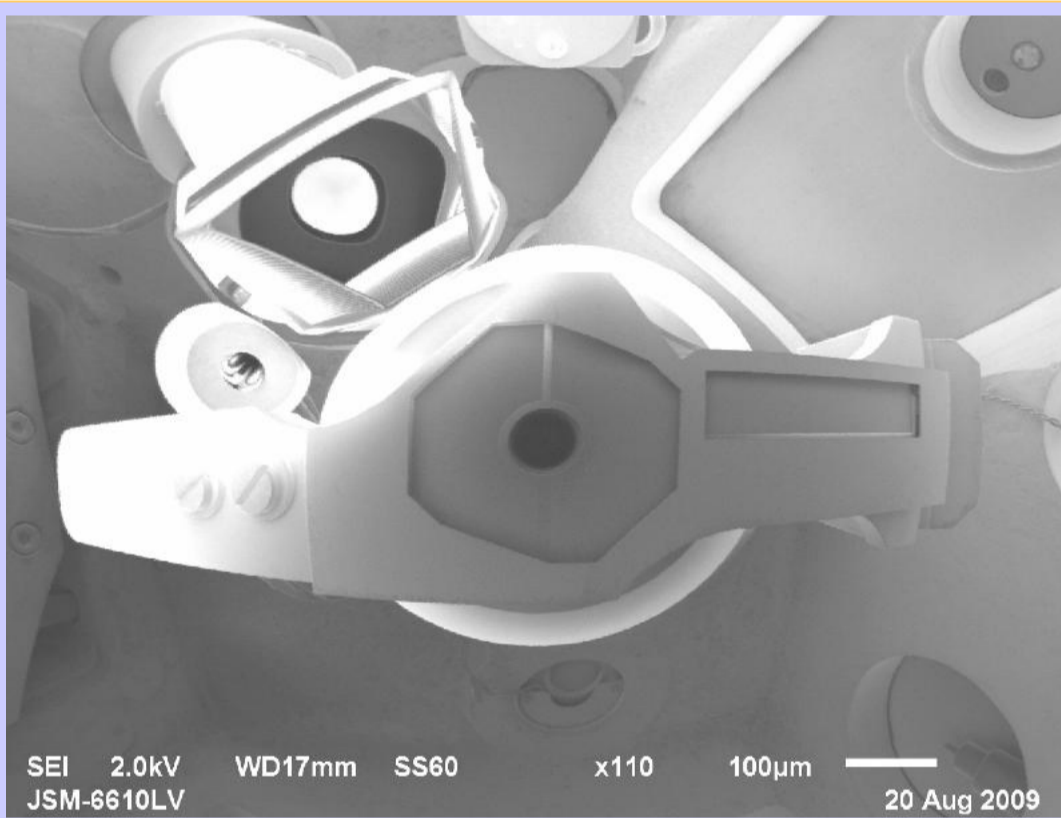
Quick Links



Happy Holidays and all the best to you in 2010!
To view our Season's Greetings and holiday scenery, please click on the image below.



Season's Greetings and Happy New Year from all of us at JEOL USA. Photo taken outside our Peabody, Massachusetts headquarters, December 2009.



Fish-eye view of SEM chamber from electron mirror image (JEOL JSM-6610LV SEM)

Technical Note: Electron Mirror, or When a Charging Sample Is Your Friend

Imaging insulators in the SEM is notoriously difficult, because the high resistivities of such samples prevent the smooth scanning of the electron beam through the sample to ground. The electrons accumulate in close proximity to the beam, raising the local potential and subsequently degrading the quality of the SEM image. Charging phenomena are dynamic and change with the sample and the imaging conditions and time. Typical solutions for imaging charging samples include conductive coating, applying sample bias and lowering imaging voltage and current. [Read the full technical note >>>](#)

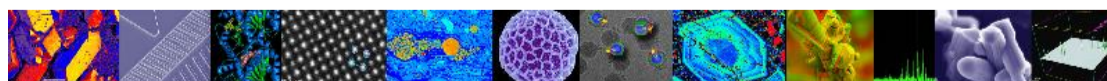
New JEOL Seminar Series 2009-10

Next Seminar: January 12, 2010 at MVA Scientific Consultants, Deluth, Georgia

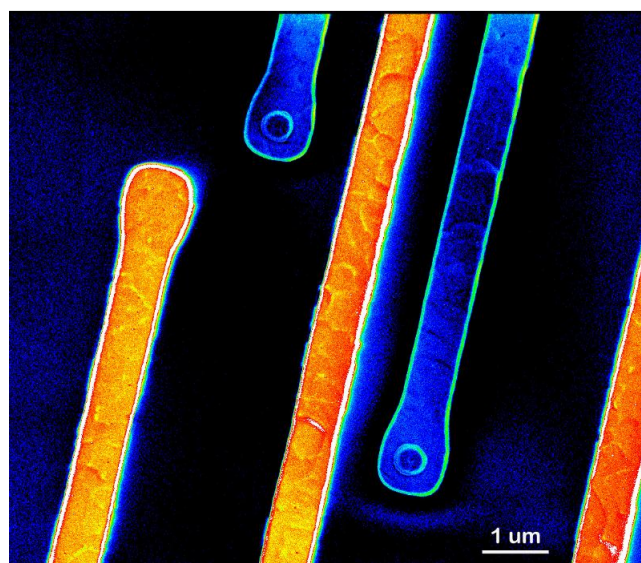
Once again JEOL is offering its customers a series of regional seminars on advances in electron microscopy. The one-day seminars are tailored to customer interests in each region and introduce recent developments in research, hardware, and software.

Topics range from atom probe tomography to cryoSEM in materials science, and from research in alternative energy sources to characterizing the impact of stents on arteries. Presentations are given by JEOL materials and biological scientists and product specialists, researchers using JEOL instruments, and suppliers.

To learn more about seminar plans for your region, contact your local JEOL sales representative or email jeolink@jeol.com.



Winning Image for 2009 EDFAS Photo Contest



A JEOL image was selected for a 2nd place award in the annual Electronic Device Failure Analysis Society (EDFAS) contest this fall. The image shows passive voltage contrast of metal lines of a de-processed ("finger lapped") IC. Blue lines are going to ground, orange lines float. The SE image was taken using 0.3 kV, then false-colored. Another JEOL image won 1st place in 2008.